Overview

The high temperature version is built up by strict final test based on stable process capability. An oscillation amplifier is supplied with a voltage regulator output apart from VDD. The voltage supply separation builds low frequency variation with supply voltage VDD. ESD and latch-up test have complied with AEC-Q100 standard.

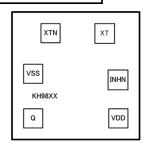
Features

2.25 to 3.63V
−40 to 125°C
Q Output "Hi-z"
Oscillation Stopped
C-MOS
C-MOS
8mA (VDD=2.25V)
15pF

Device Selection Table

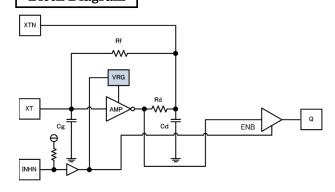
Version	Output frequency (3rd Overtone)
KH9835ALAH	90 to 140MHz
KH9835ALBH	120 to 160MHz

PAD Locations



Chip Size	0.74×0.67mm
PAD Size	90×90um
Chip Thickness	130±20um
Chip Base	VSS Level

Block Diagram

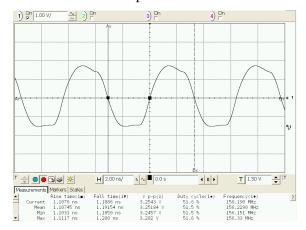


Reliability

Test Model		Perfomance	
		Values	
ESD	HBM	>4000V	
	MM	>400V	
	FI-CDM	>1000V	
Latch-up	Current Test	>200mA	
	Voltage Test	>5.4V	

Output waveform

156MHz CL=15pF VDD=3.0V



Notes: The document is a brief data sheet of the product.

Please contact with us by email for detailed data sheet, when needed.

KAHO Rev.2